



Siroquant Training

<p>DAY 1</p>	<ul style="list-style-type: none"> • XRD Basics • Powder diffraction • Description and components of powder diffractometer • XRD optimized instrumental conditions for SQ • Sample preparation for XRD analysis / Sample preparation reference to SQ • Basic Crystallography • Quantitation methods • Introduction to the Rietveld method • Basics of Siroquant Software introduction • Demo example of Siroquant. 	<p>3</p>
<p>DAY 2</p>	<ul style="list-style-type: none"> • Summary of XRD basics, Powder diffraction, Crystallography and Rietveld method • Basics of Siroquant Software introduction continued • Demo example of Siroquant. • Siroquant processes • Background subtraction and refinement • Refinement sequences • Reporting of results • Creating and using Templates • Complex example I • Complex example II 	<p>Y</p>
<p>DAY 3</p>	<ul style="list-style-type: none"> • Introduction of SiPhase Software and user databases • Preparation of HKL Files • Observed Patterns • Methods for determination of Amorphous phases Brindley Corrections • Calculations from SQ Results • Amorphous content composition • Chemical composition • Crystallite size determination • Calibration • Range of samples and examples • More discussion about SQ • Evaluation of SQ results • Limitation and important points to be considered • Questions 	<p>P</p> <p>R</p> <p>O</p> <p>G</p> <p>R</p> <p>A</p> <p>M</p>